

L Number	Hits	Search Text	DB	Time stamp
1	1025	430/394.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 10:54
2	121	(phase adj shift) and (etching adj depth) and (recess or depth or recessed)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 10:38
3	1	430/394.ccls. and ((phase adj shift) and (etching adj depth) and (recess or depth or recessed))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 10:38
4	343178	(Cr or Chrom or chromium) and (aluminum or Al)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 11:00
5	127	430/394.ccls. and ((Cr or Chrom or chromium) and (aluminum or Al))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 10:59
6	106719	(Cr or Chrom or chromium) and (aluminum)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 11:08
7	39	((Cr or Chrom or chromium) and (aluminum)) and 430/394.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 11:00
8	59824	(Cr or Chrom or chromium) same (aluminum)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 13:39
9	5582	430/5.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 11:08
10	202	((Cr or Chrom or chromium) same (aluminum)) and (430/5.ccls. or 430/394.ccls.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 11:14
11	14	((Cr or Chrom or chromium) same (aluminum)) and 430/394.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 11:09
12	195	((Cr or Chrom or chromium) same (aluminum)) and 430/5.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 11:14
13	2197	checkered	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 11:14
14	22	checkered and ((Cr or Chrom or chromium) same (aluminum))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 11:15

19	993369	multiple	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 13:03
20	259	430/394.ccls. and multiple	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 13:03
21	5	((Cr or Chrom or chromium) same (aluminum)) and (430/394.ccls. and multiple)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 13:37
22	1008059	mold or molding	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 13:37
23	362432	mask or photomask or reticle	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 13:38
24	15142	(mold or molding) and (mask or photomask or reticle)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 13:38
25	388061	etch or etching or etched	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 13:39
26	5770	((mold or molding) and (mask or photomask or reticle)) and (etch or etching or etched)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 13:39
27	457	((mold or molding) and (mask or photomask or reticle)) and (etch or etching or etched)) and ((Cr or Chrom or chromium) same (aluminum))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 13:39
28	2	checkered and (((mold or molding) and (mask or photomask or reticle)) and (etch or etching or etched)) and ((Cr or Chrom or chromium) same (aluminum)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 13:40
-	47090	contact adj holes	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/18 16:11
-	10	Checkered adj (mask or photomask or reticle)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/18 16:19
-	5577	430/5.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 11:08
-	0	(Checkered adj (mask or photomask or reticle)) and 430/5.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/18 16:15

-	283	(contact adj holes) and 430/5.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2002/09/18 16:19
-	78732	phase adj shift	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2002/09/18 16:20
-	169	((contact adj holes) and 430/5.ccls.) and (phase adj shift)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2002/09/18 16:20
-	2839	etching adj depth	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2002/09/18 16:21
-	8	((contact adj holes) and 430/5.ccls.) and (phase adj shift)) and (etching adj depth)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2002/09/18 16:30
-	1207	refraction adj factor	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2002/09/18 16:30
-	4	430/5.ccls. and (refraction adj factor)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2002/09/18 16:31
-	1274616	recess or depth or recessed	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2002/09/18 16:32
-	123	(phase adj shift) and ((contact adj holes) and 430/5.ccls.) and (recess or depth or recessed)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2002/09/18 16:33
-	121	(phase adj shift) and (etching adj depth) and (recess or depth or recessed)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2002/09/19 10:37